



## **Compliance Committee Glossary**

Version 1.3.00

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[GLOSS\_CC]

NFC Forum™

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# 1 Overview

This document provides an overview of the glossary terms used throughout document in the NFC Forum Compliance Committee.

## 1.1 Objectives

Provide a single location for all defined glossary terms.

## 1.2 Scope

This document applies only to glossary terms used by the NFC Forum Compliance Committee.

## 1.3 Audience

NFC Forum Members are the intended audience of this document.

## 1.4 Applicable Documents or References

[ADMIN_PROC_TPGV]	Administrative Process for TPG Tool Validation, NFC Forum
[ADMIN_PROC_TTV]	Administrative Process for Test Tool Validation, NFC Forum
[ANALOG_TC]	Test Cases for Analog Technical Specification, NFC Forum
[CERPOL]	NFC Forum Certification Policy, NFC Forum
[CCTCDMP]	Compliance Committee Test Case and Document Maintenance, NFC Forum
[DEVREQS]	NFC Forum Device(s) Requirements, NFC Forum
[DIGITAL_TC]	Test Cases for Digital Protocol Specification, NFC Forum
[DTA]	Device Test Application Specification, NFC Forum
[GLOSS_TC]	Technical Acronyms and Glossary NFC Forum
[ISO/IEC_17025]	ISO/IEC 17025, General requirements for the competence of testing and calibration laboratories, ISO/IEC
[LABREQS]	NFC Forum Authorized Laboratory Requirements NFC Forum
[LLCP_TC]	Test Cases for Logical Link Control Protocol Technical Specification, NFC Forum

[NCIRP]	NCIRP (NFC Forum Issue Resolution Panel) Guide, NFC Forum
[PERF_TC]	Test Cases for Tag Performance tests NFC Forum
[RFC2119]	Key words for use in RFCs to Indicate Requirement Levels, RFC 2119, S. Bradner, March 1997, Internet Engineering Task Force
[SNEP_TC]	Test Cases for Simple NDEF Exchange Protocol Technical Specification, NFC Forum
[T2T_TC]	Test Cases for NFC Forum Type 2 Tag Technical Specification, NFC Forum
[T3T_TC]	Test Cases for NFC Forum Type 3 Tag Technical Specification, NFC Forum
[T4T_TC]	Test Cases for NFC Forum Type 4 Tag Technical Specification, NFC Forum
[T5T_TC]	Test Cases for NFC Forum Type 5 Tag Technical Specification, NFC Forum
[TLAC]	NFC Forum Test Lab Audit Checklist, Latest version, NFC Forum
[TLAM]	NFC Forum Test Lab Audit Manual, Latest version, NFC Forum
TLR	Test Lab Requirements, NFC Forum
[WLC_TC]	Test Cases for Wireless Charging Technical Specification, NFC Forum

## 1.5 Administration

The NFC Forum Compliance Committee Glossary is an open document supported by the Near Field Communication Forum, Inc., located at:

401 Edgewater Place, Suite 600  
Wakefield, MA, 01880

Tel.: +1 781-876-8955  
Fax: +1 781-610-9864

<http://www.nfc-forum.org/>

The **Compliance Committee** maintains this specification.

## 1.6 Name and Logo Usage

The Near Field Communication Forum's policy regarding the use of the trademarks *NFC Forum* and the NFC Forum logo is as follows:

- Any company MAY claim compatibility with NFC Forum specifications, whether a member of the NFC Forum or not.
- Permission to use the NFC Forum logos is automatically granted to designated members only as stipulated on the most recent Membership Privileges document, during the period of time for which their membership dues are paid.
- Member's distributors and sales representatives MAY use the NFC Forum logo in promoting member's products sold under the name of the member.
- The logo SHALL be printed in black or in color as illustrated on the Logo Page that is available from the NFC Forum at the address above. The aspect ratio of the logo SHALL be maintained, but the size MAY be varied. Nothing MAY be added to or deleted from the logos.
- Since the NFC Forum name is a trademark of the Near Field Communication Forum, the following statement SHALL be included in all published literature and advertising material in which the name or logo appears:

***NFC Forum and the NFC Forum logo are trademarks of the Near Field Communication Forum.***

## 1.7 Intellectual Property

The Compliance Committee Glossary conforms to the Intellectual Property guidelines specified in the NFC Forum's *Intellectual Property Rights Policy*, as outlined in the *NFC Forum Rules of Procedure*. These documents are available on the [NFC Forum website](#).

## 1.8 Special Word Usage

The key words "MUST", "MUST NOT", "REQUIRED", "SHALL", "SHALL NOT", "SHOULD", "SHOULD NOT", "RECOMMENDED", "MAY", and "OPTIONAL" in this document are to be interpreted as described in [RFC2119].

## 2 Abbreviations

Other terms in CC documents which are not listed in Table 1 are documented in [TC\_GLOSS].

**Table 1: Abbreviations**

Abbreviation	Description	In
AC	Anti-Collision	DP_TC1,2,3
ACM	Active Communication Mode	DP_TC1,2,3, DEVREQS
AIB	Attribute Information Block	T3T_TC, WLC_TC
ALLB_REQ	ALLB_REQ Command, NFC-B	DP_TC1,2
ATL	Authorized Test Laboratory	ADMIN_PROC_TTV, TLAM, ADMIN PROC TPGV
b.n.	block number	DP_TC1
BL_NDEF_TL	Block Number containing the last Byte of the length field of the NDEF Message TLV	T2T_TC, WLC_TC
BI <sub>No</sub>	Block Number	T2T_TC
B <sub>No</sub>	Current Block Number used as B <sub>No</sub> parameter of READ_MULTIPLE_BLOCK commands.	T5T_TC
BoD	Board of Directors	CCTCDMP
BS	Bit Rate in sending Direction	LLCP_TC
BSI	British Standards Institution	DP_TC1
BT_NDEF_By <sub>No</sub>	Byte <sub>No</sub> containing the tag field of the NDEF Message TLV	WLC_TC
CC	Compliance Committee	ADMIN_PROC_TTV, CCTCDMP
CC_0, CC_1, CC_2, CC_3, CC_4, CC_5, CC_6, CC_7	Respectively Byte 0, 1, 2, 3 and for an 8 byte Capability Container bytes 4, 5, 6, and 7 of the Capability Container contained in the T5T Tag.	T5T_TC
CCC	Car Connectivity Consortium®	DEVREQS
CCL <sub>EN</sub>	Length of the Capability Container in bytes	T5T_TC, T4T_TC
CCTCDMP	Compliance Committee Test Case and Document Maintenance	TLAM
CE	Card Emulation	DEVREQS
COTS	Commercial off the Shelf	TLAM
CR	Change Request	CCTCDMP
CTTV <sub>P</sub>	Conformance Test Tool Validation Procedure	ADMIN_PROC_TTV, ADMIN PROC TPGV
DATA <sub>MemLayout</sub> (x,y)	Byte y of the row x in the memory layout MemLayout. When y is not specified, it is the T5T Block from the memory layout MemLayout	T5T_TC
DIDI	The Initiator Device Identification Number	LLCP_TC
DIDT	Target Device Identification Number	LLCP_TC
DTA	Device Test Application	DP_TC1,2,3, DEVREQS
EGT <sub>B,LISTEN</sub>	Extra Guard Time for LISTEN, NFC-B	DP_TC1,2,3
EGT <sub>B,POLL</sub>	Extra Guard Time for POLL, NFC-B	DP_TC1,3

ERMB_REQ	EXTENDED_READ_MULTIPLE_BLOCK_REQ	T5T_TC
ERMB_RES	EXTENDED_READ_MULTIPLE_BLOCK_RES	T5T_TC
FCI	File Control Information	T4T_TC
FID	File Identifier	T4T_TC
FO	Frame Option, NFC-B	DP_TC1
FSC <sub>B,MIN</sub>	Frame Size for Proximity Card – NFC – B	DP_TC1
FSC <sub>T4AT,MIN</sub>	Frame Size for Proximity Card – T4AT	DP_TC1
FSD <sub>T4AT,MIN</sub>	Frame Size for Proximity Coupling Device – T4AT	DP_TC1
FSD <sub>T4BT,MIN</sub>	Frame Size for Proximity Coupling Device – T4BT	DP_TC1
FWI <sub>B,MAX</sub>	Frame Waiting Time Integer – NFC – B	DP_TC1
FWI <sub>T4AT,MAX</sub>	Frame Waiting Time Integer – T4AT	DP_TC1
FWT <sub>B,SENSB</sub>	Frame Waiting Time – NFC-B	DP_TC1,2
FWT <sub>ISODEP,DEACTIVATION</sub>	Frame Waiting Time – ISO-DEP Protocol	DP_TC1
FWT <sub>T4AT,ACTIVATION</sub>	Frame Waiting Time – T4AT Protocol	DP_TC1
GUI	Graphical User Interface	SNEP_TC
ICS	Implementation Conformance Statement	T3T_TC, T2T_TC, ADMIN_PROC_TTV, TLAM, DEVREQS, PERF_TC
ILCT	Inter Lab Comparison Testing	TLAM
INF	INformation field	DP_TC1,3
IUT	Implementation Under Test	DP_TC1, T5T_TC, T4T_TC, T3T_TC, T2T_TC, ANALOG_TC, WLC_TC, PERF_TC
IXIT	Implementation eXtra Information for Testing	T4T_TC, T3T_TC, T2T_TC, ADMIN_PROC_TTV
LOCK_BLOCK/LB	Lock block commands are supported (LOCK_SINGLE_BLOCK and/or EXTENDED_LOCK_SINGLE_BLOCK).	T5T_TC
LRT	Length ReducTion	DP_TC1,3
LT	Lower Tester	DP_TC1, T5T_TC, T4T_TC, T3T_TC, T2T_TC, ANALOG_TC, WLC_TC, PERF_TC
MBNo_T5TArea	Last block number covering the T5T_Area	T5T_TC
MBREAD/MB	READ_MULTIPLE_BLOCK command supported (READ_MULTIPLE_BLOCK, and/or EXTENDED_READ_MULTIPLE_BLOCK).	T5T_TC
MOTS	Modified off the Shelf	TLAM
MU	Measurement Uncertainty	TLAM
MVx.y	Mapping Version x.y	T4T_TC

NCIRP	NFC Forum Certification Issue Resolution Panel	ADMIN_PROC_TTV, ADMIN_PROC_TPGV
NDA	NDEF Detection and Access group	T5T_TC, T4T_TC, T2T_TC
NLEN	Length of the NDEF Message	T5T_TC, T4T_TC
NMD	NFC Mobile Device	DEVREQS
OSI	Open Systems Interconnection	DEVREQS
P_AID	Proprietary Application Identifier	DP_TC1
PCM	Passive Communication Mode	DEVREQS
PFB	Protocol Format Byte	LLCP_TC
PI	Protocol Info	DP_TC1
PR_data	Proprietary Response Data	DP_TC1
R/W	Read / Write	DEVREQS
r_date	revision number suffix to the end of the filename	CCTCDMP
REVT	Reference Equipment Verification Tests	TLAM
RMB_REQ	READ_MULTIPLE_BLOCK_REQ	T5T_TC
RMB_RES	READ_MULTIPLE_BLOCK_RES	T5T_TC
RQ	Requirement Catalog	DP_TC1, T5T_TC, T4T_TC, T3T_TC, T2T_TC, SNEP_TC, PERF_TC
RQ Reference	NFC Forum Specification – Requirement Reference	DP_TC1, T5T_TC, T4T_TC, T3T_TC, T2T_TC, ANALOG_TC, WLC_TC, PERF_TC
RTOS	Recognized Test Laboratory Organizations	TLAM
RWT <sub>ACM,NFCDEP,ACTIVATION</sub>	Response Waiting Time for Active Communication Mode	DP_TC1
RWT <sub>NFCDEP,ACTIVATION</sub>	Response Waiting Time	DP_TC1
SDD_REQ	Single Device Detection Request	DP_TC1
SDD_RES	Single Device Detection Response	DP_TC1,2
SEL_REQ	SElect REQuest Command, NFC-A	DP_TC1,2
SEL_RES	SElect RESponse Command	DP_TC1,2
SENS_REQ	SENS_REQ Command, NFC-A	DP_TC1
SENS_RES	Response to ALL_REQ and SENS_REQ Command, NFC-A	DP_TC1,2
SENSB_REQ	SENSB_REQ Command, NFC-B	DP_TC1,2
SENSB_RES	Response to ALLB_REQ and SENSB_REQ Command, NFC-B	DP_TC1,2
SENSF_REQ	SENSF_REQ Command, NFC-F	DP_TC1,2
SENSF_RES	Response to SENSF_REQ	DP_TC1
SFGI <sub>B,MAX</sub>	Start-up Frame Guard Time Integer – NFC – B	DP_TC1
SFGI <sub>T4AT,MAX</sub>	Start-up Frame Guard Time Integer – T4AT	DP_TC1
SLP_REQ	SLP_REQ Command	DP_TC1
SLPB_REQ	SLPB_REQ Command	DP_TC1,2
SPECIAL_FRAME	Special Frame option for Write-Alike commands	T5T_TC



SW	Status Words	DP_TC1
T4AT	Type 4A Tag, when the statement only applies to a T4T based on NFC-A	DP_TC1,2,3, T4T_TC
T4BT	Type 4B Tag, when the statement only applies to a T4T based on NFC-B	DP_TC1,2,3, T4T_TC
T5T-MNB	Maximum value of the number of data blocks (NB) parameter in the READ_MULTIPLE_BLOCK and EXTENDED_READ_MULTIPLE_BLOCK commands supported by the implementation under test (IUT).	T5T_TC
TC	Test Case	DP_TC1,2,3, T2T_TC, SNEP_TC
TC ID	Test Case Identifier (code)	T3T_TC, T2T_TC, PERF_TC
TCCL	Test Case Categories List	ADMIN_PROC_TTV, CCTCDMP, TLAM, ADMIN_PROC_TPGV
TCMT	Test Case Mapping Table	ADMIN_PROC_TPGV
TLAC	Test Lab Audit Checklist	TLAM
TLAM	Test Lab Audit Manual	TLAM
TLR	Test Lab Requirements	TLAM
TP	Test Purpose	T5T_TC
TPG Tool	Test Plan Generator Tool	ADMIN_PROC_TPGV
TSS	Test Suite Structure	T5T_TC
TT	Tolerance Time	DP_TC1,2,3
TTVR	Test Tool Validation Report	ADMIN_PROC_TTV
TTVTF	TPG Tool Validation Task Force	ADMIN_PROC_TPGV
TVA	Tool Validation Administrator	CCTCDMP
TWG	Testing Working Group, the WG responsible to manage the test cases	ADMIN_PROC_TTV, CCTCDMP, ADMIN_PROC_TPGV
USI	Universal Stylus Initiative	DEVREQS, WLC_TC
WG	Working Group of the Compliance Committee	CCTCDMP
WT <sub>NFCDEP,MAX</sub>	Waiting Time, parameter to code RWT <sub>NFCDEP,ACTIVATION</sub>	DP_TC1

### 3 Glossary Terms

#### $\Delta SFGT_B$

*Start-up Frame Guard Time. Minimum Frame Delay Time after an ATTRIB response for a Type 4B Tag platform*

#### $\Delta SFGT_{T4AT}$

*Start-up Frame Guard Time. Minimum Frame Delay Time after an Answer To Select, NFC-A (ATS) for a Type 4A Tag platform.*

#### *Accreditation*

The process by which a third-party accreditation body assesses the compliance of an organization to a process standard. For the purposes of the NFC Forum Certification Program, Accreditation amounts to conformance to the standard [ISO/IEC\_17025] and is awarded by accreditation bodies that are members of the International Laboratory Accreditation Co-operation (ILAC) and that conform to the ILAC Multilateral Agreement for Recognition (MLA).

#### *Active Communication Mode*

See [GLOSS\_TC].

#### *Activity*

See [GLOSS\_TC].

#### *Applicable Certification Requirements*

For a particular product or Certified Implementation, this is the complete list of items in force or active at the time of submission of Certification Information to the Certification Administrator. See [CERPOL].

#### *Authorized Test Laboratory*

A laboratory that has satisfied and continues to satisfy all requirements set in Section 11 of this document, and is thereby authorized to provide certification testing services to Suppliers.

#### *Bit Duration*

$1 \text{ bd} = 128/(\mathbf{f}_C \times \mathbf{D}_{\text{POLL} \rightarrow \text{LISTEN}})$  or  $1 \text{ bd} = 128/(\mathbf{f}_C \times \mathbf{D}_{\text{LISTEN} \rightarrow \text{POLL}})$

#### *Card Emulator*

See [GLOSS\_TC].

#### *Certificate*

A document (issued to Suppliers) that formally declares that a device is a Certified Implementation.

#### *Certification Administrator (CA)*

The organization appointed by the NFC Forum to manage the day-to-day operations of the Certification Program in accordance with the policies defined in this document.

*Certification Agreement*

The agreement between the Supplier and the Certification Administrator (CA) that defines the certification service to be provided and contains the legal commitment by the Supplier to the conditions of the Certification Program.

*Certification Information*

The complete set of information about a product that is submitted to the Certification Administrator (CA) in support of an application for certification.

*Certification Register*

The official list of all Certified Implementations and related information that is maintained by the Certification Administrator (CA) and made available on the Certification Program website.

*Certification Release*

A Certification Release is a group of consistent Test Cases and process documents, to aid product procurement, development and certification. For a given Certification Release, the set of interoperability modules and features that need to be supported by NFC-Forum-compliant devices, are defined in a particular version of [DEVREQS]. Each feature is defined by requirements in Technical Specifications. NFC Forum releases at least one version of a set of consistent Test Cases documents, called a Test Release. New versions of Test Cases documents MAY lead to new Test Releases for the same Certification Release. Only one version of Test Release can be active at any given time for one Certification Release. All active documents for a Certification Release are available on the Certification Program website.

*Certification Testing*

Testing that an NFC Forum Implementation is REQUIRED to undergo to achieve certification.

*Certified Implementation*

An active NFC Forum Implementation that has successfully completed the certification process and for which the Supplier has been notified in writing by the Certification Administrator (CA) that certification has been achieved.

*Collision*

See [GLOSS\_TC].

*Command*

See [GLOSS\_TC].

*Conformance Testing*

Set of tests defined for the purpose of determining whether an implementation complies with the set of specifications defined by the NFC Forum.

*Connectionless Transport*

See [GLOSS\_TC].

*Connection-oriented Transport*

See [GLOSS\_TC].

*Correct Frame*

See [GLOSS\_TC].

*Cyclic Redundancy Check (CRC)*

See [GLOSS\_TC].

*Data Link Connection*

See [GLOSS\_TC].

*Device Test Application (DTA)*

Part of the DUT that is used for the NFC Forum Certification Test.

In digital testing, IUT is the layer that corresponds to the [DIGITAL] and [ACTIVITY] specifications, embedded in an NFC Forum Device provided for [DIGITAL\_TC].

In analog testing, IUT is the layer that corresponds to the [ANALOG] specifications, embedded in an NFC Forum Device provided for [ANALOG\_TC].

In LLCP testing, IUT is the layer that corresponds to the [LLCP] specifications, embedded in an NFC Forum Device provided for [LLCP\_TC].

In SNEP testing, IUT is the layer that corresponds to the [LLCP] and [SNEP] specifications, embedded in an NFC Forum Device provided for [SNEP\_TC].

*Device Under Test (DUT)*

NFC Forum Device that contains the Implementation Under Test (IUT).

*Digital Certification Testing*

A defined set of tests that checks the software responsible for the data exchange between an NFC Forum Device and another NFC Forum Device or tag. The tests check the **Error! Reference source not found.** and **Error! Reference source not found..**

**D**<sub>LISTEN→POLL</sub>

See [GLOSS\_TC]

**D**<sub>POLL→LISTEN</sub>

See [GLOSS\_TC].

*Engineering Sample*

A prototype, commercial, or certified NFC Forum Device. In the context of test tool validation, it is a sample used to verify that the tool correctly executes a test case.

*Implementation Conformance Statement (ICS)*

A checklist of the capabilities supported by an NFC Forum Implementation. The ICS provides an overview of the features and options of the Specifications that are implemented, including the modes of operation that the product supports. See [CERPOL]. The ICS is used to select and parameterize test cases and serves as an indicator of basic interoperability between different products; see [NCIRP] . An ICS for a protocol is usually known as a PICS (Protocol Implementation Conformance Statement).

*Implementation Under Test (IUT)*

Part of the DUT that is used for the NFC Forum Certification Test.

- In digital testing, IUT is the layer that corresponds to the [DIGITAL] and [ACTIVITY] specifications, embedded in an NFC Forum Device provided for [DIGITAL\_TC].
- In analog testing, IUT is the layer that corresponds to the [ANALOG] specifications, embedded in an NFC Forum Device provided for [ANALOG\_TC].
- In LLCP testing, IUT is the layer that corresponds to the [LLCP] specifications, embedded in an NFC Forum Device provided for [ANALOG\_TC].
- In SNEP testing, IUT is the layer that corresponds to the [LLCP] and [SNEP] specifications, embedded in an NFC Forum Device provided for [SNEP\_TC].

*Initiator*

See [GLOSS\_TC].

*Installation*

The process of Technology Detection, Collision Resolution, and Device Activation Activities.

*Interoperability Module*

An interoperability module provides the basis for communication and interaction between components of the NFC Forum architecture.

*Interoperability Testing*

Set of tests that are followed in order to determine whether a product interacts successfully with other products to comply with a set of functionalities specified by the NFC Forum.

*Interpretation*

A decision made by the NFC Forum NCIRP (NFC Forum Issue Resolution Panel) that elaborates or refines the meaning of a device specification in [CCTCDMP] Compliance Committee Test Case and Document Maintenance, NFC Forum

[DEVREQS], of an NFC Forum Specification, or of an external standard referenced by either of them. An Interpretation is one possible outcome of a Problem Report (PR).

*ISO-DEP Protocol*

See [GLOSS\_TC].

*IUT Test Plan*

The list of parameterized test cases applicable to the IUT. This list is an outcome of the NFC Forum Test Specification, TCCL (Test Case Category List), and the Supplier's ICS documents. Each IUT within an NFC Forum Implementation has its own IUT Test Plan.

*Link MIU*

See [GLOSS\_TC].

*Listen Mode*

See [GLOSS\_TC].

*Listening Device*

An NFC Forum Device in Listen Mode.

*LLCP Certification Testing*

A defined set of tests that checks the software that is responsible for the data exchange between an NFC Forum Device and another NFC Forum Device. The **Error! Reference source not found.** shall be checked.

*LLCP Link*

See [GLOSS\_TC].

*Local LLC*

See [GLOSS\_TC].

*Logical Data Link*

See [GLOSS\_TC].

*Lower Tester (LT)*

The representation of the means of providing, during test execution, indirect control, and observation of the lower service boundary of the IUT via the underlying service-provider (from ISO/IEC 9646).

*Maximum Information Unit (MIU)*

See [GLOSS\_TC].

*Modulation Index*

See [GLOSS\_TC].

*Mute*

Behavior of a device in Listen Mode not sending a response. If the Listen device is configured to support the ACM Target mode it keeps its Operating Field condition to Operating Field OFF.

*Mute ACM*

The switch from Operating Field On to Operating Field Off and no frame has been sent during the time the field was On. Applicable timing parameters and associated limits are defined in [ACTIVITY].

*NCIRP Participant*

An individual representing an NFC Forum member company whose participation in the NCIRP has been sanctioned by the Compliance Committee.

*NFC Forum Card Emulation Mode*

The mode used when an NFC Universal Device is using the part of the NFC Forum Protocol Stack that responds to Master/Slave Communication from a reader/writer terminal. When in NFC Forum Card Emulation Mode, the NFC Universal Device (emulating either an NFC Forum Tag or a contactless card) cannot start communication on its own. The Master/Slave Communication is initiated by a reader/writer terminal. The communication for this mode is abbreviated as CE.

*NFC Forum Certification Issue Resolution Panel (NCIRP)*

The NFC Forum committee responsible for responding to Problem Reports (PRs) and Notices of Non-compliance.

*NFC Forum Component*

An element or part of a NFC Forum Implementation (e.g., antenna, protocol stack, etc.).

*NFC Forum Device*

See [GLOSS\_TC].

*NFC Forum Device Requirements*

The definition of the parts of the NFC Forum Protocol Stack that are REQUIRED to be present in a product for it to be eligible for certification. NFC Forum Device Requirements include separate definitions for Peer Mode, Reader/Writer Mode, and Card Emulation Mode, and defines the Certification Release. It is defined in document [DEVREQS]. See Section 4.1 of [CERPOL].

*NFC Forum Functionality*

A set of features defined in the NFC Forum Specifications.

*NFC Forum Implementation*

The combination of hardware, software and mechanical components that together deliver NFC Forum Functionality and that meets the requirements defined in [CCTCDMP] Compliance Committee Test Case and Document Maintenance, NFC Forum [DEVREQS].

*NFC Forum Issue Resolution Chair (NIRC)*

An independent third party responsible for chairing the NCIRP and managing all related activities.

*NFC Forum Peer Mode*

The mode used when an NFC Forum Device is using the part of the NFC Forum Protocol Stack that enables Peer-to-Peer Communication with another NFC Forum Device using this same mode. The initiator starts the communication and the target responds to it. Both NFC Forum Devices have the capability to be either initiator or target. This mode uses the NFC-DEP Protocol as described in **Error! Reference source not found..** The communication for this mode is abbreviated as P2P.

*NFC Forum Reader/Writer Mode*

The mode used when an NFC Forum Device is using the part of the NFC Forum Protocol Stack that enables Master/Slave Communication with NFC Forum tags or contactless cards. The NFC Forum Device starts the Master/Slave Communication and sends commands to an NFC Forum tag or contactless card. The communication for this mode is abbreviated as RW.

*NFC Forum Test Specification*

The set of tests and testing-related information that the NFC Forum uses to confirm the compliance of an Implementation Under Test (IUT) to the corresponding NFC Forum Specifications.

*NFC Reader Device*

See [GLOSS\_TC].

*NFC Tag Device*

See [GLOSS\_TC]

*NFC Universal Device*

See [GLOSS\_TC].

*NFC-A*

See *Technology* in [GLOSS\_TC].

*NFC-B*

See *Technology* in [GLOSS\_TC].

*NFC-DEP Protocol*

See [GLOSS\_TC].

*NFC-F*

See *Technology* in [GLOSS\_TC].

*NFCID0*

See *NFCIDx* in [GLOSS\_TC].

*NFCID1*

See *NFCIDx* in [GLOSS\_TC].

*NFCID1 CLn*

See [GLOSS\_TC].

*NFCID2*

See *NFCIDx* in [GLOSS\_TC].

*NFCID3*

See *NFCIDx* in [GLOSS\_TC].

*NFC-V*

See *Technology* in [GLOSS\_TC].

*«noise» error*

Transmission error in a Response that is encapsulated in a frame of at least 4 characters, encapsulated in a frame with residual bits (i.e., the number of data bits is not a multiple of 8).



*Notice of Non-compliance*

A formal notice to the NFC Forum that the NFC Forum in its sole judgment finds to be credible, indicating that a Certified Implementation is not compliant for any reason.

*Open ecosystem Device Classes*

All the Device Classes that are dedicated to the open ecosystem and ensuring use case independent interoperability.

*Operating Field*

See [GLOSS\_TC].

*Operating Field Off*

See [GLOSS\_TC].

*Operating Field On*

See [GLOSS\_TC].

*Operating Volume*

See [GLOSS\_TC].

*Passive Communication*

See [GLOSS\_TC].

*Platform*

Platform refers to a set of common design, components, and technology elements that serve as a foundation for a series of related products sharing the same NFC Component. This includes legacy port-based devices and host bridges to peripheral buses, and most controllers integrated into the system.

*Poll Command*

- See [GLOSS\_TC].

*Poll Mode*

See [GLOSS\_TC].

*Polling Device*

An NFC Forum Device in Poll Mode.

*Problem Report (PR)*

A description of a question about clarification, intent, or correctness related to a specification or a test case. If a PR is accepted by the NCIRP, the PR will be resolved into an Interpretation or a Test Case Deficiency (TCD).

*Profile*

See [GLOSS\_TC].

*Protocol Data Unit (PDU)*

See [GLOSS\_TC].

*Reader/Writer*

See [GLOSS\_TC].

*Record Type Definition (RTD)*

An NFC Forum RTD defines NDEF payload data formats and their associated type names. The generic RTD guidelines are defined in **Error! Reference source not found..**

*Remote LLC*

See [GLOSS\_TC].

*Reset*

See [GLOSS\_TC].

*Response*

See [GLOSS\_TC].

*Service [LLCP]*

See [GLOSS\_TC].

*Service Discovery Protocol (SDP)*

See [GLOSS\_TC].

*Smart Card (SC)*

A contactless tag or smart card based on one of the technologies (ISO/IEC\_14443A, ISO/IEC\_14443B, or JIS\_X\_6319-4) compatible with those defined by the NFC Forum (NFC-A, NFC-B, or NFC-F).

*Specific market ecosystem Device Classes*

All the Device Classes that are dedicated to specific market segments to enable a single particular use case, called, specific market ecosystem. An example is the set of Device Classes for the Automotive market. Typically, the Specific market ecosystem Device Classes serve the needs of specific standardization bodies other than NFC Forum and benefiting from the NFC Forum certification program.

*Specifications*

The detailed technical documents that are published by the NFC Forum and that define the radio frequency and protocol capabilities and behaviors that deliver NFC functionality. The Specifications MAY include, by reference, specifications and standards published by other organizations.

*State*

See [GLOSS\_TC].

*Sub-cases*

A set of scenarios within a test case.

*Subject Matter Expert (SME)*

An expert about a specific technique, standard, specification, technology, etc.

*Supplier*

A product vendor who is interested in or applying for certification, or has certified a product in the NFC Forum Certification Program.

 $T_{A,nn}$ 

Minimum time period during which the NFC Forum Listen Device NFC-A is not allowed to produce any detectable disturbance before it sends its response.

 $T_{B,nn}$ 

Minimum time period during which the NFC Forum Listen Device NFC-B is not allowed to produce any detectable disturbance before it sends its response.

*Target*

See [GLOSS\_TC].

*Technology*

See [GLOSS\_TC].

*Technology Subset*

See [GLOSS\_TC].

*Test Case*

A description of the testing of one or more requirements derived from a specification.

*Test Case Categories List (TCCL)*

A list of test cases categorized in terms of the conditions under which they are to be used in Certification Testing. See Section 8.3.1 of [CERPOL].

*Test Case Deficiency (TCD)*

An error in an NFC Forum test case that is agreed by the NCIRP to be causing an IUT to produce an incorrect result that impacts the IUT's certification. A Test Case Deficiency is one possible outcome of a Problem Report.

*Test Case Mapping Table (TCMT)*

TCMT provides required test cases based on IUT's ICS values.

*Test Environment*

Test environment required to perform NFC Forum Certification Testing. It includes the Device Test Application, Implementation Under Test, and the Lower Tester.

*Test Functionalities*

Functionalities to be implemented by the vendor following the requirements specified in this document, and to be implemented in the Device Test Application to allow the Test Laboratory to proceed to NFC Forum Certification Testing.

*Test Group*

A set of test cases grouped together by the NFC Forum to be the smallest set available for inheritance of test results.

*Test Laboratory*

A facility approved by the NFC Forum to perform NFC Forum Certification Testing.

*Test Plan*

A collection of Test Cases in one document.

*Test Plan Generator (TPG)*

The tool that creates a test plan according to an ICS/IXIT (<https://nfc-forum-tpg.com>).

*Test Release*

The NFC Forum MAY publish new versions of its Test Specifications and, when they are published, will collect the new versions into consistent sets to aid product certification and testing. Each such set is called a Test Release.

*Test Script*

The implementation of a Test Case into a specific test tool using a scripting language. Depending on the test tool, the Test Script can be contained in a single file, distributed over several files, or be parameter driven, or it can be in text form, giving the operator test instructions.

*Test Track*

A test track involves conformance testing, interoperability testing, or a combination of the two.

*Tool Validation Administrator (TVA)*

Someone appointed by the NFC Forum to manage the test tool validation process through approval of the test tool for certification testing.

*Type X Tag*

See [GLOSS\_TC].

*Type Y Tag Platform*

The command set and underlying communication protocol of a Type Y Tag according to [DIGITAL].

NOTE When used in a document, “Y” must be replaced by “2”, “3”, “4A”, “4B” or “5”.

*Type-Length-Value (TLV)*

See [GLOSS\_TC].

*Validation House*

An independent third-party test laboratory selected by the NFC Forum for conducting the test tool validation process.

*Vendor*

The entity that submits the NFC Forum Device for NFC Forum Certification Testing.

*Waiver*

Expressed or implied voluntary and intentional relinquishment or abandonment of a requirement.

*Waiver Request*

A request through a Problem Report to get a waiver for business reasons.

*WLC Reader Device*

An NFC Forum Device that supports the following Modus Operandi: Reader/Writer and WLC Poller. It can also support RF Collision Avoidance.

See [WLC], [GLOSS\_TC], [ACTIVITY]

*WLC Tag Device*

An NFC Forum Device that supports the following Modus Operandi: at least one Tag Module and the WLC Listener functionality.

See [WLC], [GLOSS\_TC]

*WPC Ki Reader Device*

An NFC Forum Device that supports the following Modus Operandi: Reader/Writer and WPC Poller. It can also support RF Collision Avoidance.

See [WPC Ki Comm], [GLOSS\_TC], [ACTIVITY]

*WPC Ki Tag Device*

An NFC Forum Device that supports the following Modus Operandi: at least one Tag Module and the WPC Listener functionality.

See [WPC Ki Comm], [GLOSS\_TC]

## A. Revision History

Table 1 outlines the revision history of Compliance Committee Glossary.

**Table 2: Revision History**

Document Name	Revision and Release Date	Status	Change Notice	Supersedes
Compliance Committee Glossary	1.0 Initial Version 28 Sept 2016	Approved	Approved by the CC	
Compliance Committee Glossary	1.0.02 30 Apr 2017	Approved	Additions per MloI WG, [CCTCDMP] Compliance Committee Test Case and Document Maintenance, NFC Forum  [DEVREQS]; approved by CPWG; added audit related documents; final edit.	1.0 Initial Version
Compliance Committee Glossary	1.0.03 2018-04-19	Final	Referring to GLOSS_TC were possible instead of having own definitions	1.0.02 30 Apr 2017
Compliance Committee Glossary	1.0.04 2019-10	Approved	Added “Type X Tag”, “Type Y Tag Platform” and editorial updates	1.0.03 2018-04-19
Compliance Committee Glossary	1.0.05 2020-12	Approved	Added “Mute” and “Mute ACM”	1.0.03 2018-04-19
Compliance Committee Glossary	1.0.06 2021-10	Approved	Aligned definition of Certification Release with other certification documents	1.0.05 2020-12
Compliance Committee Glossary	1.1.01 2022-03	Approved	Added new terms: WLC Reader Device, WLC Tag Device, Open ecosystem Device Classes, Specific market ecosystem Device Classes  Removal of T1T	1.0.06 2021-10
Compliance Committee Glossary	1.1.02 2023-10-11	Approved	Editorial update	1.1.01 2022-03
Compliance Committee Glossary	1.2.00 2024-06-17	Approved	Added new terms: WPC Ki Reader Device, WPC Ki Tag Device,	1.1.02 2023-10-11

Compliance Committee Glossary	1.3.00 2025-03- 10	Approved	Added abbreviations	1.2.00 2024-06-17
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